Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/015,613	BAUDISCH, PATRICK	
Examiner	Art Unit	

Aaron M. Richer

2676

	SEARCHED				
Class	Subclass	Date	Examiner		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
EAST (US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB) - See Search History Printout	3/1/2006	AMR
345/1.3 (text search only)	3/1/2006	AMR